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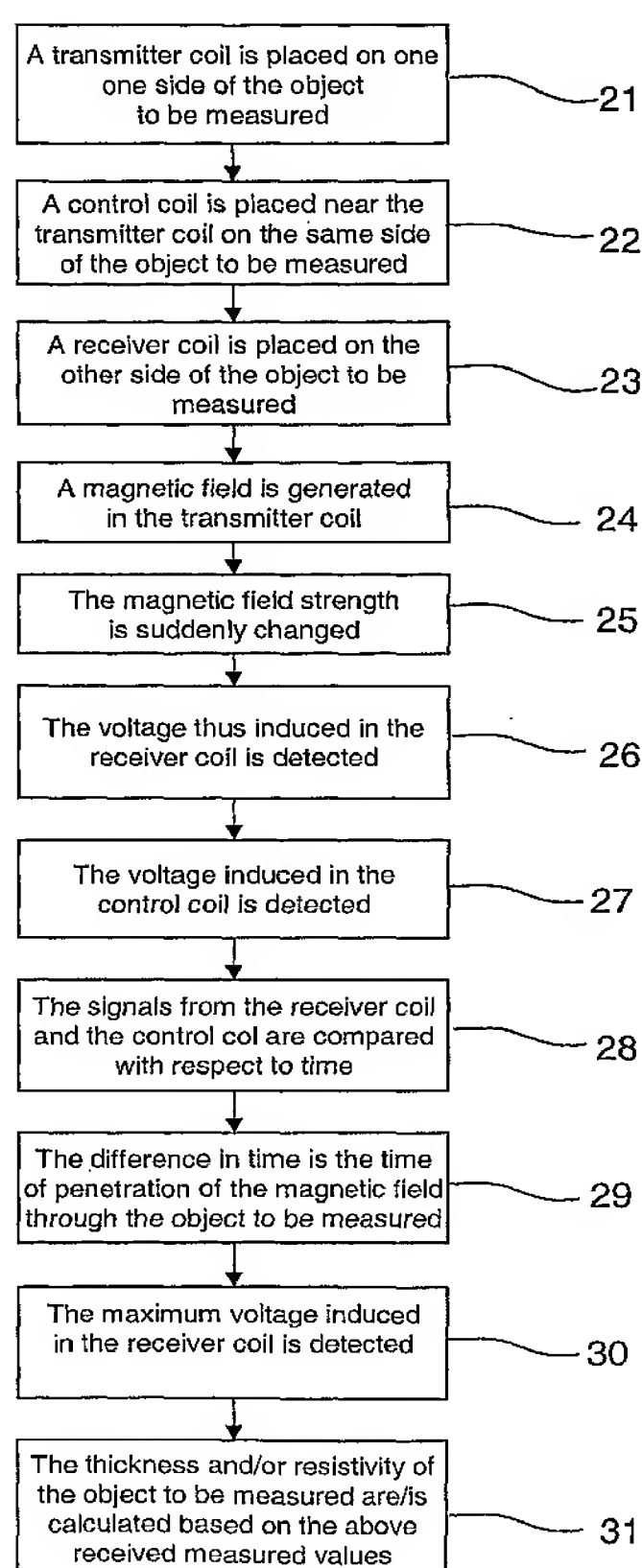
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(54) Title: A METHOD AND A DEVICE FOR ELECTROMAGNETIC MEASUREMENT OF THICKNESS AND ELECTRICAL CONDUCTIVITY



(57) Abstract: The invention relates to a method for non-contact determination of sought properties of an object to be measured (2), such as, for example, its geometrical dimension or its electrical conductivity, by using electromagnetic induction, and wherein an electromagnetic field is generated in a transmitter coil (3), placed on one side of the object (2) to be measured, and wherein the magnetic field penetrating through the object (2) to be measured is detected by a receiver coil (4) placed on the other side of the object (2) to be measured. The invention comprises: placing a control coil (5) near the transmitter coil (3) generating a change in the magnetic field of the transmitter coil (3), detecting the field change in the control coil (5), detecting the field in the receiver coil (4), determining the difference in time for the detection of the field change in the control coil (5) and in the receiver coil (4), respectively, determining the time of penetration (T₂) through the object (2) to be measured, and determining therefrom the thickness or electrical conductivity of the object (2) to be measured.

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